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In the Specification

Please amend the specification of this application as follows:

Rewrite the paragraph at page 1, lines 4 to 10 as follows:

--This application claims the priority under 35 U.S.C. 119(e)(1) of the following co-pending U.S. provisional applications: 60/186,326 ~~(Docket TI-30526)~~ filed on March 2, 2000 now U.S. Patent Application Serial No. 09/798,173; and 60/219,340 ~~(Docket TI-30498)~~ originally filed on March 2, 2000 as non-provisional U.S. Serial No. 09/515,093 and thereafter converted to provisional application status by a petition granted on August 18, 2000.--

Rewrite the paragraph at page 2, lines 11 to 16 as follows:

--Functional testing, wherein a designer is responsible for generating test vectors that are intended to ensure conformance to specification, still remains a widely used test methodology. For very large systems this method proves inadequate in providing a high level of detectable fault coverage. Automatically generated test ~~patters~~ patterns would be desirable for full testability, and controllability and observability are key goals that span the full hierarchy of test (from the system level to the transistor level).--

Rewrite the paragraph at page 2, line 17 to page 3, line 2 as follows:

--Another problem in large designs is the long time and substantial expense involved. It would be desirable to have testability circuitry, system and methods that are consistent with a concept of design-for-reusability. In this way, subsequent devices and systems can have a low marginal design cost for testability, simulation and emulation by reusing the testability, simulation and emulation circuitry, systems and methods that are